

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Attorney Docket No.: UCF-341DIV (which is a divisional of application SN: 10/141,582 filed 05/08/2002).

Filed: \_\_\_\_/\_\_\_\_/\_\_\_\_

First Named Inventor: HONGWEN REN

For: TUNABLE ELECTRONIC LENS AND PRISMS USING INHOMOGENEOUS NANO SCALE LIQUID CRYSTAL DROPLETS

Examiner: NGUYEN, HOAN C.

Group: 2871

INFORMATION DISCLOSURE STATEMENT

Honorable Commissioner of Patents  
and Trademarks  
Washington DC 20231

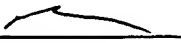
Sir:

Pursuant to 37 CFR §§ 1.97 and 1.98, record is being made below in a form PTO-1449 of documents which the Patent Office may wish to consider in connection with examination of the above-identified patent application. It is respectfully requested that the cited documents be carefully considered by the Examiner and made of record in this case. As provided in § 1.97(g), no representation is made or intended that a thorough art search was made. As provided in 37 C.F.R. § 1.97(h), this Supplemental Information Disclosure Statement does not constitute an admission of any kind, and specifically is not an admission that the documents listed on the attached PCT-1449 are, or are considered to be, material to the patentability of the above-identified patent application, as defined in 37 C.F.R. § 1.56(b).

Copies of the cited references were previously submitted to the USPTO in the parent application No.: 10/141,582 filed May 8, 2002 and made of record. Applicants claim priority to said application under 35 U. S. C. §120. Accordingly, copies of those documents are not provided with this Statement pursuant to 37 CFR § 1.98(d).

It is respectfully requested that the cited documents be carefully considered by the Examiner and made of record in the case.

Respectfully submitted,

  
Brian S. Steinberger  
Law Offices of Brian S. Steinberger, P.A.  
PTO Registration No. 36,423  
101 Brevard Avenue  
Cocoa, Florida  
(321) 633-5080 (321) 633-9322 Fax  
Customer No.: 23717

Date: 12/31/03

**US DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE**

**APPLICANT: HONGWEN REN AND SHIN-TSON WU**  
**FOR: TUNABLE ELECTRONIC LENS AND PRISMS USING INHOMOGENEOUS**  
**NANO-SCALE LIQUID CRYSTAL DROPLETS**

10997 U.S. PTO  
 10/141582  
 05/08/02

**LIST OF ART CITED BY APPLICANT**

**U.S. PATENT DOCUMENTS**

EXAMINER	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS
CE AA	4,572,616 ✓	02/25/86	Kowel, et al.	350	335
AB	5,299,289 ✓	03/29/94	Omae, et al.	359	95
AC	5,764,317 ✓	06/09/98	Sadovnik	349	5
AD	6,061,107 ✓	05/09/00	Yang, et al.	349	86
AE	6,072,552 ✓	06/06/00	Komura, et al.	349	86
AF	6,184,954 B1 ✓	02/06/01	Inoue, et al.	349	86
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AH	6,218,679 B1 ✓	04/17/01	Takahara, et al.	257	59
AI	6,221,443 B1 ✓	04/24/01	Kubota, et al.	428	1.1
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**FOREIGN PATENT DOCUMENTS**

NONE

**OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)**

NONE

*Hoan Chau Nguyen*      *10/15/03*

<b>Notic of R ferences Cited</b>	Application/Control No. 10/141,582		Applicant(s)/Patent Under Reexamination REN ET AL.	
	Examiner HOAN C. NGUYEN		Art Unit 2871	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Nam	Classification
	A	US-6437925	08-2002	Nishioka	359/726
	B	US-6545739	04-2003	Matsumoto et al.	349/198
	C	US-6128056	10-2000	Kubota et al.	349/86
	D	US-5963283	10-1999	Omae et al.	349/86
	E	US-5093735	03-1992	Doane	349/92
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.